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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/440,595	11/15/1999	NAVEED MAJID	PHA-23843	3147
75	90 09/25/2002			
CORPORATE PATENT COUNSEL			EXAMINER	
US PHILIPS CORPORATION 580 WHITE PLAINS ROAD			PAREKH, NITIN	
TARRYTOWN, NY 10591			ART UNIT	PAPER NUMBER
			2811	
			DATE MAILED: 09/25/2002	

Please find below and/or attached an Office communication concerning this application or proceeding.



Application No. 09/440,595

Applicant(s)

Examiner

Art Unit

Majid et al

Office Action Summary

Nitin Parekh 2811

MAILING DATE of this communication appears on the cover sheet with the correspondence address

	The WAILING DATE of this communication appears	on the cover sneet with the correspondence address			
	for Reply				
	ORTENED STATUTORY PERIOD FOR REPLY IS SET MAILING DATE OF THIS COMMUNICATION.	TO EXPIRE 3 MONTH(S) FROM			
- Extensi	sions of time may be available under the provisions of 37 CFR 1.136 (a). In	n no event, however, may a reply be timely filed after SIX (6) MONTHS from the			
mailing - If the p	g date of this communication. period for reply specified above is less than thirty (30) days, a reply within th	the statutory minimum of thirty (30) days will be considered timely.			
- If NO p		and will expire SIX (6) MONTHS from the mailing date of this communication.			
- Any rep	ply received by the Office later than three months after the mailing date of t patent term adjustment. See 37 CFR 1.704(b).				
Status	patent term adjustment. See S7 S. F. F. S. (2).				
	Responsive to communication(s) filed on Jul 2, 200	02 .			
		tion is non-final.			
	closed in accordance with the practice under Ex pa	except for formal matters, prosecution as to the merits is arte Quayle, 1935 C.D. 11; 453 O.G. 213.			
	tion of Claims				
4) [X]	Claim(s) <u>1-7</u>	is/are pending in the application.			
4	a) Of the above, claim(s)	is/are withdrawn from consideration.			
5) 🗆	Claim(s)	is/are allowed.			
6) 💢	Claim(s) <u>1-7</u>	is/are rejected.			
	Claim(s)				
		are subject to restriction and/or election requirement.			
· · ·	tion Papers				
	The specification is objected to by the Examiner.				
10)	The drawing(s) filed on is/are	e a) \square accepted or b) \square objected to by the Examiner.			
_	Applicant may not request that any objection to the d				
11)		is: a)□ approved b)□ disapproved by the Examiner.			
	If approved, corrected drawings are required in reply t				
	The oath or declaration is objected to by the Exami	iner.			
	under 35 U.S.C. §§ 119 and 120	,			
	Acknowledgement is made of a claim for foreign pr	riority under 35 U.S.C. § 119(a)-(d) or (f).			
a) 🗀	☐ All b)☐ Some* c)☐ None of:				
1	1. Certified copies of the priority documents have				
	2. Certified copies of the priority documents have been received in Application No				
	application from the International Burea				
	ee the attached detailed Office action for a list of the	e certified copies not received.			
. —	Acknowledgement is made of a claim for domestic				
a) 🗌	a a marting of the control of the co				
	Acknowledgement is made of a claim for domestic	priority under 35 U.S.C. §§ 120 and/or 121.			
Attachme					
~	tice of References Cited (PTO-892) tice of Draftsperson's Patent Drawing Review (PTO-948)	4) Interview Summary (PTO-413) Paper No(s).			
, .	2) X Notice of Draftsperson's Patent Drawing Review (PTO-948) 5) Notice of Informal Patent Application (PTO-152) Notice of Informal Patent Application (PTO-152) 6) Other:				
o, 🕰	mation disclosure statement(s) (FTO-1770) Labor 190(s).	o) Uther:			

DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-7 are rejected under 35 U.S.C. 103(a) as being unpatentable over Uchida et al (US Pat. 6060748) in view of Oka et al (6140690), Takagi et al (US Pat. 6130458) and Lauffer et al (IDS-paper #4, European Pat. 0471938A1).

Regarding claim 1, Uchida et al disclose a multichip integrate circuit (IC) module (MCM)/device comprising:

-a high power semiconductor device (130, 130a and 130b in Fig. 1) such as MOS type field effect transistor (FET), bipolar transistor, etc. formed on a silicon-0n-insulator (SOI) substrate region (100 in Fig. 1; Col. 4, line 45- Col. 5, line 5) and a low power/low speed device (140 and 140a in Fig. 1) such as a transistor (Col. 5) formed on a silicon/bulk technology substrate region (120 in Fig. 1; Col. 5, line 16), and

- the high power and low power semiconductor devices/chips being directly mounted on a substrate (100/110/120, 200, 210, 11, etc. in Fig. 1-3)

(Fig. 1-3; Col. 4, line 45-Col. 7, line 10).

Uchida et al fail to specify the low power device/chip being a control chip and the power chip and control chip being directly mounted on the electrically conductive heat sink connected to ground potential.

Oka et al teach using a MCM where a power device (50 in Fig. 4 and 5) having a high voltage/current is disposed on a common substrate with a weak/low signal device (60 in Fig. 5) functioning as a control and a sensor device (Col. 2, line 15-25; Col. 5; Col. 17).

Lauffer et al teach using a multichip module having a variety of chips such as high power, low power, memory, logic chip, etc. comprising a bulk/conventional technology device and SOI device being directly mounted on the electrically conductive heat sink/substrate made of copper (11 in Fig. 4; Col. 9, line 7) which is connected to a ground potential (Col. 12, line 32).

Takagi et al teach using a multichip hybrid integrate circuit (IC)/module comprising a high/low level power semiconductor chips (200 in Fig. 12A and B) and respective high/low level control semiconductor chips (100 in Fig. 12A and B) devices

being directly mounted on an electrically conductive substrate connected to ground potential (81 in Fig. 12B; Col. 11, line 30-Col. 12, line 57).

The cited reference by Hill (US Pat. 6028348, Fig. 3; Col. 2, line 66) teach using a multichip module with the chips mounted on a conventional metal/electrically conductive substrate which serves as a heat sink.

Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate a MCM having a power chip and a control chip being directly mounted on an electrically conductive heat sink substrate connected to ground potential so that heat dissipation and temperature distribution can be improved using Oka et al, Lauffer et al and Takagi et al's chip/substrate structures in Uchida et al's multichip module.

Regarding claims 2-4, Uchida et al fail to specify the control chip comprising BIMOS, CMOS or bipolar device.

Takagi et al disclose the control semiconductor chips comprising CMOS or any other conventional configurations comprising BICMOS, bipolar, n-MOS, etc. (Col. 13, line 64).

Therefore, it would have been obvious to a person of ordinary skill in the art at the time invention was made to incorporate a control chip comprising BIMOS, CMOS or bipolar device so that the current handling/breakdown voltage capability can be

improved Oka et al, Lauffer et al and Takagi et al's chip/substrate structures in Uchida

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et al's multichip module.

Regarding claims 5-7, the claim elements have been addressed as explained above in

the rejection for claim 1.

Response to Arguments

2. Applicant's arguments with respect to claims 1-7 have been considered but are

moot in view of the new ground(s) of rejection.

Papers related to this application may be submitted directly to Art Unit 2811 by

facsimile transmission. Papers should be faxed to Art Unit via Technology Center 2800

fax center located in Crystal Plaza 4, room 4C23. The faxing of such papers must

conform with the notice published in the Official Gazette, 1096 OG 30 (15 November

1989).

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Nitin Parekh whose telephone number in (703) 305-

3410. The examiner can be normally reached on Monday-Friday from 08:30 am-5:00

pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Tom Thomas, can be reached on (703) 308-2772. The fax number for the organization where this application or proceeding is assigned is (703) 308-7722 or 7724.

Nitin Parekh

09-12-02

Steven Loke